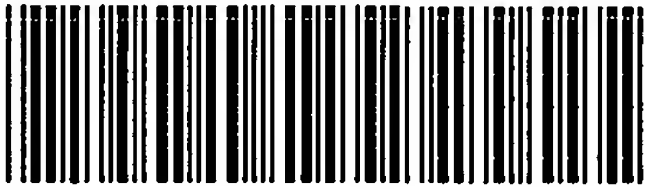


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/608,184	KIM, HYOUNG-IL	
	Examiner	Art Unit	
	Elias B. Hiruy	2837	

SEARCHED			
Class	Subclass	Date	Examiner
			1

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched East: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	10/3/2005	EH
Searched IEEE using key words	9/21/2005	EH
(Several Plural many numerous) near3 control\$4) and accuracy and overshoot and delay and response and settling and time	10/3/2005	EH
motor and (driv\$4 near3 (environment\$1 condition)) and ((several plural many numerous) near3 control\$4) and (control\$3 near	10/3/2005	EH
Requested a fast and focused search from STI	10/3/2005	EH